

ProductNews

New Lesker Rectangular Vacuum Valves



As applications for Rectangular Gate Valves keep getting larger, Kurt J. Lesker Company is meeting the demand for the wider rectangular valve openings commonly used for semiconductor processing, solar panels, LCD/flat panel, and other vacuum coating applications. Our new valves are rated up to 2 million cycles and available with 200 mm through 2,000 mm openings. These KJLC rectangular valves are proven ideal for vacuum applications that require large valve openings.

Kurt J. Lesker Company
www.lesker.com

ATLAS from Carl Zeiss Offers New Opportunities in the Nanoscopic Analysis of Large-Area Samples

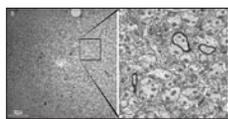
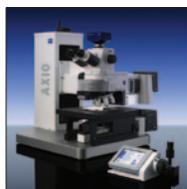


Photo: J. Mendenhall UT, Austin

Carl Zeiss launched ATLAS™, a powerful hardware and software package, which, in combination with any scanning electron microscope from Carl Zeiss, enables quick and efficient imaging of large-area specimens with nanometer resolution. With suitable specimens, unattended operation can acquire multi-image montages that span extremely large fields of view, permitting capture of regions on the millimeter scale with resolution on the nanometer scale in a handful of hours.

Carl Zeiss SMT AG
www.smt.zeiss.com

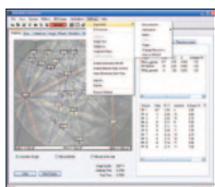
Axio Imager Vario Upright Microscope for Materials Examinations



Carl Zeiss introduced the Axio Imager Vario, a microscope module for industrial tasks where large samples requiring various contrasting methods are examined. The sample space of the Axio Imager Vario has been adapted to object sizes with up to 300-mm lateral and up to 250-mm vertical extension. This microscope combines excellent optics with a stably designed column construction. Sample stages with travel distances of up to 300 mm can be used.

Carl Zeiss MicroImaging, Inc.
www.zeiss.com/micro

EDAX Introduces OIM™ 6.0



EDAX Inc. released OIM™ 6.0—the first microanalysis package to be written for 64-bit processor and Microsoft® Windows 7 compatibility with datasets reaching >40 million data points. OIM™ software offers easier access to the most commonly used functions along with one button analysis.

Among the latest features incorporated into OIM™ 6.0 are expanded QuickGen and Template functionality, full-image area mapping, easier data rotations, and interactive page colors.

AMETEK EDAX
www.edax.com

The NeoScope Benchtop SEM Now at McCrone



Introducing the NeoScope Benchtop SEM, a device that economically complements both optical microscopes and traditional SEMs. The NeoScope makes it simple to obtain high magnification images with high resolution and large depth of field using a microscope that is as simple to operate as a digital camera, but with the powerful electron optics of an SEM. Now you'll be seeing images with a focus and depth of field well beyond that of any optical microscope.

McCrone Microscopes & Accessories
www.mccronemicroscopes.com

OmniMet® 9.5 Image Acquisition and Analysis Software



Buehler's new OmniMet 9.5 image acquisition and quantitative analysis software improves lab efficiency and increases operator appeal compared to previous generations of the product. Specific improvements include browsing the database using a typical PC-style folder interface, the ability to store multimedia files (such as instruction files, written procedures, and measurement reports), a preview pane to view thumbnail images of files within a folder, the ability to flip and rotate images, and overlay grids.

Buehler
www.buehler.com

CRAIC Technologies Release New 64-Bit Windows 7 Microspectroscopy Software



CRAIC Technologies, released the 64-bit version of its MINERVA™ microspectroscopy software package. This software is designed to collect, analyze, and process microspectra™ from CRAIC microspectrophotometers running 64-bit versions of Windows 7®. MINERVA-64™ is designed for both industrial processes and scientific research. It is simple to use yet contains many advanced spectroscopic control and analysis features.

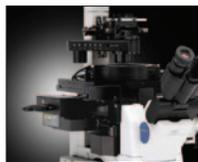
CRAIC Technologies, Inc.
www.microspectra.com

The SJ-F Series Offers High-Speed, Wide-Area Static Elimination with High-Precision Ion Balance

The new static eliminator resolves unwanted static charges and the potential for dust adhesion, damage to electronic devices, and other production or quality concerns caused by static. KEYENCE's SJ-F series combines powerful fans with an integrated sensing system to provide the fastest wide-area static elimination in its class. The I.C.C control method monitors ion balance and environmental conditions, including dust buildup on the electrodes, to offer a typical ion balance of ± 1 V.

Keyence Corporation
www.keyence.com/usa.php

Olympus IX81[®]-ZDC2 Zero Drift Inverted Microscope System



Olympus introduced the new IX81[®]-ZDC2 Zero Drift microscope system, a motorized inverted microscope with a comprehensive, integrated autofocus solution for investigators doing time-lapse experiments. The system's next-generation autofocus system operates continuously so that it maintains focus even when events happen very quickly. In addition, the system easily can be set to operate in a discrete, one-shot mode designed to facilitate applications that require maintaining multiple focus positions, such as experiments involving multi-well imaging.

Olympus America Scientific Equipment Group
www.olympusamerica.com

Thermo Fisher Scientific Combines EDS and WDS with New EBSD Option for NORAN System 7 Microanalysis System



Thermo Fisher Scientific Inc. launched the QuasOr EBSD option for its all-in-one microanalysis solution, NORAN System 7. The new system combines Electron Backscatter Diffraction (EBSD) with Energy Dispersive Spectroscopy (EDS) and Wavelength Dispersive Spectroscopy (WDS) capabilities in a single software interface. Thermo Scientific QuasOr is fully integrated into the NORAN System 7 microanalysis platform, providing a single interface for the simultaneous collection of EBSD, EDS, and WDS.

Thermo Fisher Scientific Inc.
www.thermofisher.com

Andor Launches NIR-Optimized CCD for High-Throughput Photovoltaic Inspection

Andor Technology plc announced the launch of the iKon-M PV Inspector, a dedicated CCD camera that is designed to deliver market-leading speed and sensitivity performance for in-line electroluminescence and photoluminescence inspection of photovoltaic cells. The PV Inspector benefits from thermoelectric cooling down to -70 °C for minimization of darkcurrent. Andor's proven Ultravac[™] hermetic vacuum process provides both sustained cooling and unparalleled longevity through absolute protection of the exposed sensor surface.

Andor Technology plc
www.andor.com/pvinspector

CRAIC Technologies Introduces the Universal C-mount Adapter for Microscope Cameras and Spectrophotometers



CRAIC Technologies introduces its Universal C-mount Adapter for Microscope Cameras and Spectrophotometers, which allows a camera or a spectrophotometer to be parfocal and parcentral with the eyepieces on the microscope. It can be mounted on the open photoports of many microscope brands. Featuring X, Y, and Z adjustment and a range of photoport flanges, the adapter makes using cameras and spectrophotometers attached to microscopes much easier to use.

CRAIC Technologies, Inc.
www.microspectra.com/

TDIS[™] Micro-Rheometer Imaging Stage



Harrick Scientific Products' TDIS[™] (Tissue Deformation Imaging Stage) is a micro-rheometer designed for upward-looking confocal and fluorescence microscopes. The TDIS[™] is capable of measuring the shear and compression properties of soft biological samples such as cartilage, sclera, and corneal tissue with simultaneous imaging. Fine spatial variations in the mechanical properties of these materials can be measured. Samples up to 1 cm on a side can be accommodated. The TDIS[™] is compatible with equipment manufactured by Leica, Nikon, and other manufacturers.

Olympus, and Zeiss.
Harrick Scientific Products, Inc.
www.harricksci.com

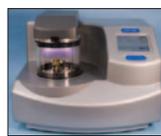
New ReVél Diamond Abrasive Grinding Discs Reduce Polishing Time



Buehler's ReVél ("reveal") diamond abrasive grinding/polishing discs for tool steels, tungsten carbide, and inconel prepares specimens from planar grind to final polish in four to seven minutes, reducing total polishing time by 63 to 78 percent, cleaning/changeover time by 25 percent, the number of steps by 25 percent, and the number of consumables by 33 percent. ReVél's diamond abrasive nanotechnology features diamond particles for high removal rates coated with smaller colloidal silica particles for polishing.

Buehler
www.buehler.com

EMS Series of Rotary-Pumped Modular Coating Systems



Electron Microscopy Sciences now offers the EMS 150R, a compact rotary-pumped coating system. The modular EMS150R can be configured in three formats: a sputter coater suitable for standard (tungsten) SEM specimen coating and sputtering of a wide range of non-oxidizing (noble) metals, such as gold (Au), platinum (Pt), silver (Ag) and palladium (Pd); a carbon coater ideal for SEM EDS and WDS applications; or a combined sputter carbon coater system.

Electron Microscopy Sciences
www.emsdiasum.com

Leica Microsystems Adds Routine Stereomicroscope Leica M60 to Its Successful M Series



The latest high-performance generation of the well-known Leica M series has been extended to include the new Leica M60 Stereomicroscope. Leica Microsystems therefore now offers a whole family of stereomicroscopes designed according to the modular CMO (Common Main Objective) principle: the Leica M50, M60, and M80. Featuring superlative optical quality, an intelligent range of accessories, and smooth interplay of all components, this series masters even exceptional challenges with ease.

Leica Microsystems
www.leica-microsystems.com